

WSF20N20G

N-Ch MOSFET

General Description

The WSF20N20G is N-channel Enhanced VDMOSFETs, is obtained by the self-aligned planar Technology which reduce the conduction loss, improve switching .

performance and enhance the avalanche energy. The transistor can be used in various power switching circuit for system miniaturization and higher efficiency..

Features

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent Cdv/dt effect decline
- Green Device Available

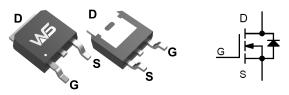
Product Summery

BVDSS	RDSON	ID
200V	0.12Ω	18A

Applications

- Uninterruptible Power Supply(UPS)
- Power Factor Correction (PFC)

TO-252 Pin Configuration



Symbol	Parameter	Rating	Units
V _{DS}	Drain-Source Voltage	200	V
V _{GS}	Gate-Source Voltage	±20	V
I _D @T _C =25℃	Continuous Drain Current, V _{GS} @ 10V ¹	18	А
I _D @T _C =100℃	Continuous Drain Current, V _{GS} @ 10V ¹	10	A
I _{DM}	Pulsed Drain Current ²	72	А
EAS	Single Pulse Avalanche Energy ³	340	mJ
I _{AS}	Avalanche Current	15	A
P₀@T₀=25℃	Total Power Dissipation ³	104	W
T _{STG}	Storage Temperature Range -55 to 1		°C
TJ	Operating Junction Temperature Range -55 to 150		°C

Thermal Data

Symbol	Parameter	Тур. Мах.		Unit	
R _{0JA}	Thermal Resistance Junction-ambient ¹		60	°C/W	
R _{eJC}	Thermal Resistance Junction-Case ¹		1.2	°C/W	

Absolute Maximum Ratings



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Electrical Characteristics (T_J=25¹C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =250uA	200			V
$\triangle BV_{DSS} / \triangle T_J$	BVDSS Temperature Coefficient	Reference to 25 $^\circ\!\mathrm{C}$, I_D=1mA		0.25		V/℃
R _{DS(ON)}	Static Drain-Source On-Resistance ²	V _{GS} =10V , I _D =4.5A		0.12	0.16	Ω
V _{GS(th)}	Gate Threshold Voltage		2.0	3.5	4.0	V
$ riangle V_{GS(th)}$	V _{GS(th)} Temperature Coefficient	VGS-VDS, IB -2500A		-4.63		mV/℃
	Drain-Source Leakage Current	V_{DS} =200V , V_{GS} =0V , T_{J} =25 $^{\circ}\mathrm{C}$			1	uA
I _{DSS}	Drain-Source Leakage Current	V_{DS} =160V , V_{GS} =0V , T_{J} =125 $^{\circ}$ C			10	
I _{GSS}	Gate-Source Leakage Current	V_{GS} = $\pm30V$, V_{DS} =0V			±100	nA
R _g	Gate Resistance	V _{DS} =0V , V _{GS} =0V , f=1MHz		0.12		Ω
Qg	Total Gate Charge (10V)	V _{DS} =160V , V _{GS} =10V , I _D =18A		40		nC
Q _{gs}	Gate-Source Charge			5.2		
Q _{gd}	Gate-Drain Charge			18		
T _{d(on)}	Turn-On Delay Time	V _{DD} =100V , V _{GS} =10V , R _G =25Ω,I _D =18A		24		
Tr	Rise Time			45		
T _{d(off)}	Turn-Off Delay Time			101		ns
T _f	Fall Time			95		
C _{iss}	Input Capacitance	V _{DS} =25V , V _{GS} =0V , f=1MHz		1317		
Coss	Output Capacitance			181		pF
C _{rss}	Reverse Transfer Capacitance			76		

Guaranteed Avalanche Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
EAS	Single Pulse Avalanche Energy ⁵	V _{DD} =25V , L=0.1mH , I _{AS} =15A	250			mJ

Diode Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current ^{1,6}	V _G =V _D =0V , Force Current			18	A
I _{SM}	Pulsed Source Current ^{2,6}	$v_{\rm G}$ - $v_{\rm D}$ - $0v$, Force Current			72	А
V _{SD}	Diode Forward Voltage ²	V _{GS} =0V , I _S =18A , TJ=25℃			1.4	V
t _{rr}	Reverse Recovery Time			230		nS
Qrr	Reverse Recovery Charge	IF=15A , dl/dt=100A/ μs , T _J =25 $^\circ C$		1.8		uC

Note :

1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper,t<10sec.

2.The data tested by pulsed , pulse width $\,\leq\,$ 300us , duty cycle $\,\leq\,$ 2%

3. The EAS data shows Max. rating . The test condition is $V_{\text{DD}}\text{=}25\text{V}, V_{\text{GS}}\text{=}10\text{V}, \text{L=}0.1\text{mH}, \text{I}_{\text{AS}}\text{=}15\text{A}$

4. The power dissipation is limited by 150°C junction temperature

5. The Min. value is 100% EAS tested guarantee.

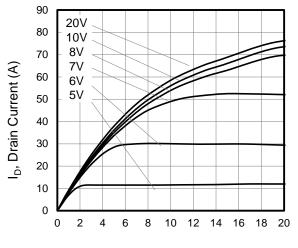
6.The data is theoretically the same as I_D and I_{DM} , in real applications, should be limited by total power dissipation.

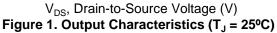


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Typical Characteristics





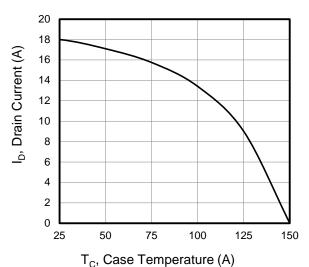
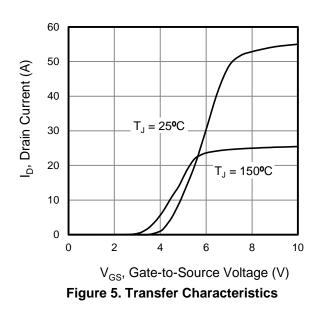
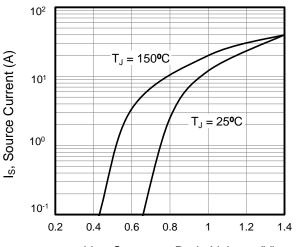
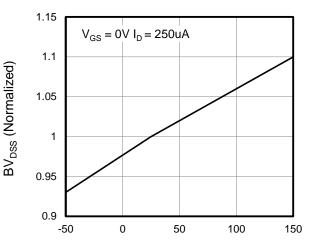


Figure 3. Drain Current vs. Temperature





V_{SD}, Source-to-Drain Voltage (V) Figure 2. Body Diode Forward Voltage



T_J, Junction Temperature (^oC) Figure 4. BV_{DSS} Variation vs. Temperature

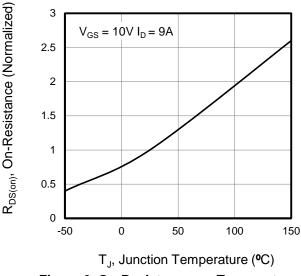
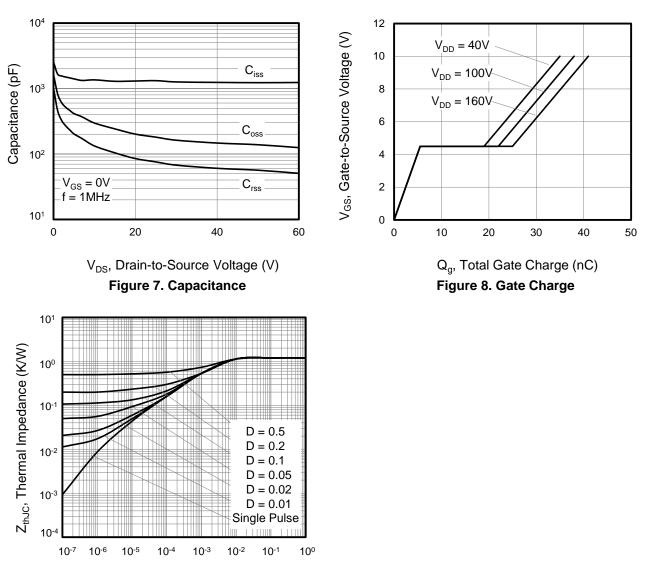


Figure 6. On-Resistance vs. Temperature





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T_p, Pulse Width (s) Figure 10. Transient Thermal Impedance



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